

Notice of References Cited		Application/Control No. 10/526,403	Applicant(s)/Patent Under Reexamination WHITEHEAD ET AL.	
		Examiner David S. Baker	Art Unit 2884	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,216,249 A	06-1993	Jones et al.	250/370.05
*	B	US-4,465,932 A	08-1984	Burgemeister, Eduard A.	250/370.07
*	C	US-4,266,138 A	05-1981	Nelson et al.	378/34
*	D	US-2007/0148079 A1	06-2007	Scarsbrook et al.	423/446
*	E	US-2004/0182308 A1	09-2004	Scarsbrook et al.	117/068
*	F	US-2004/0221795 A1	11-2004	Scarsbrook et al.	117/068
*	G	US-5,210,430 A	05-1993	Taniguchi et al.	257/103
H	US-				
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Isberg J., Hammersberg J., Johansson E., Wikstrom T., Twitchen D., Whitehead A., Coe S., Scarsbrook G.; "High Carrier Mobility in Single-Crystal Plasma-Deposited Diamond"; 06 September 2002; Science; Volume 297; Pages 1670-1672.
	V	Schmid G.J., Koch J.A., Lerche R.A., Moran M.J.; "A Neutron Sensor Based on Single Crystal CVD Diamond"; 29 March 2004; Nuclear Instruments & Methods in Physics Research Section A; Volume 527; Pages 554-561.
	W	Twitchen D.J., Whitehead A.J., Coe S.E., Isberg J., Hammersberg J., Wikstrom T., Johansson E.; "High-Voltage Single-Crystal Diamond Diodes"; May 2004; IEEE Transactions on Electron Devices; Volume 51; Number 5; Pages 826-828.
	X	Isberg J., Hammersberg J., Bernhoff H., Twitchen D.J., Whitehead A.J.; "Charge Collection Distance Measurements in Single and Polycrystalline CVD Diamond"; 2004; Diamond and Related Materials; Volume 13; Pages 872-875.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/526,403	WHITEHEAD ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Permegger H., Roe S., Weilhammer P., Eremin., Frais-Kolbl H., Griesmayer E., Kagan H., Schnetzer S., Stone R., Trischuk W., Twitchen D., Whitehead A.; "Charge-Carrier Properties in Synthetic Single-Crystal Diamond Measured with the Transient-Current Technique"; 2005; Journal of Applied Physics; Volume 97; Pages 073704.1-073704.9.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.